ROCHESTER INSTITUTE OF TECHNOLOGY MICROELECTRONIC ENGINEERING

History of MEMS at RIT

Dr. Lynn Fuller

Webpage: <u>http://people.rit.edu/lffeee</u> Microelectronic Engineering Rochester Institute of Technology 82 Lomb Memorial Drive Rochester, NY 14623-5604 Tel (585) 475-2035 Fax (585) 475-5041 Email: <u>Lynn.Fuller@rit.edu</u> Department webpage: <u>http://www.microe.rit.edu</u>

Rochester Institute of Technology

Microelectronic Engineering

11-28-2011 history of MEMS.ppt

© Nov ember 28, 2011 Dr. Lynn Fuller



MEMS TIME LINE

1982 Microelectronic Engineering Program Starts 1986 RIT Dedicates Microelectronic Engineering Cleanroom 1987 First Graduates of MicroE and Start of RIT's First Full Time Masters Program in Engineering (ME MME) 1989 First MEMS Research Project – Industry Sponsor 1990 First Federally Funded MEMS Research Project 1991 First Senior Project on MEMS 1994 First MEMS Patent Issued to RIT 1995 Student Run Factory to Manufacture CMOS Devices 1996 First Masters Thesis on MEMS Devices 1997 Incubator to Provide Lab Access for Start Up Companies 1999 First MEMS Courses Taught at RIT 2000 First Short Course on MEMS for Industry People 2001 First MEMS Courses Taught in Mechanical Engineering 2002 Start of the Ph.D. Program in Microsystems Engineering 2003 First NSF Funded MEMS Curriculum Development Project and First MEMS Course Taught by EE 2011 First MEMS Ph.D. Student, Journal Publication, 2nd MEMS Patent **Rochester Institute of Technology** Microelectronic Engineering



FIRST MEMS RESEARCH PROJECT - MICRO GAS CHROMATOGRAPHY



RIT'S FIRST MEMS PATENT – DR. LANE, 1994

United States Patent [19]	[11] Patent Number: 5,357,803
Lane	[45] Date of Patent: Oct. 25, 1994
[54] MICROMACHINED MICROACCELEROMETER FOR MEASURING ACCELERATION ALONG THREE AXES	Film Transducers", Sensors and Actuators, vol. 4, p 173-182, Dec. 1983. L. M. Roylance, et al., "A Batch-Fabricated Silice Accelerometer", IEEE Trans. Electron Devices, vo ED-26, No. 12, pp. 1911-1917, Dec. 1979.
[75] Inventor: Richard L. Lane, Penfield, N.Y.	K. E. Petersen, "Silicon as a Mechanical Material"
 [73] Assignee: Rochester Institute of Technology, Rochester, N.Y. [21] Appl. No.: 866.667 	Proc. IEEE, vol. 70, No. 5, pp. 420-457, May 1982. M. E. Motamedi, "Acoustic Accelerometers", IEE. Trans. Ultrason. Ferroelec. Freq. Contr., vol. UFFC-3
[22] Filed: Apr. 8, 1992	Pau-Ling Chem, et al., "Integrated Silicon Microbear
[51] Int. Cl. ³ G01P 15/13 [52] U.S. Cl. 73/517 B; 361/280 [58] Field of Search 73/517 B; 517 R; 516 R; 361/280, 283.1; 310/309; 384/439	PI-FET Accelerometer", <i>IEEE Trans. Electron Devices</i> , vol. ED-29, No. 1, pp. 27-33, Jan. 1982. F. Rudolf, et al., "Silicon Microascelerometer", <i>Trans. ducers</i> '87, Rec. of the 4th Int. Conf. on Solid-State Sers ora dA Actuators, 1987, pp. 395-398.
[56] References Cited U.S. PATENT DOCUMENTS 3,742,767 7/1973 Bernard et al	Primary Examiner—John E. Chapman Attorney, Agent, or Firm—Nixon, Hargrave, Devans & Doyle
4,068,533 1/1978 Ferriss 73/517 B	[57] ABSTRACT
4.353.061 9/1982 Matrone	The present invention relates to a microacceleromete employing a single free-mass and capable of measurin acceleration along three coordinate axes, and a proces for fabricating through micromachining and microacle tronic techniques a microaccelerometer employing free-mass. A microaccelerometer preform is cor structed by chemically coating and etching a silico wafer to form a support member and a free-mass up or under the the member. The free mass is provided by the
OTHER PUBLICATIONS G. Bomchil, et al. "Formation and Oxidation of Porous Silicon for Silicon on Insulator Technologies" Energy Beam-Solid Interactions and Transient Thermal Process- ing, 1985, pp. 463-474. D. W. Satchell, et al. "Silicon Microengineering for Accelerometers", Rec. of the Int. Conf. on the Mech. Technol of Inertial Devices, 1987, pp. 191-193.	rounded by the member. The free-mass is movable wit respect to, but constrained by the silicon support mem- ber. Acceleration measurements are obtained by ci- cuits which sense changes in the position of the free mass with respect to an equilibrium position, induced b a change in the rate of acceleration of the accelerom ter, and the electromagnetic force required to restor the free-mass to its equilibrium position.
Richard S. Muller, "Heat and Strain-Sensitive Thin	18 Claims, 6 Drawing Sheets

US005357803A		5 357 803
[11]	Data of Datast	0.4.25.1004
[45]	Date of Patent:	Oct. 25, 1994
73-182, M. Ro Accelero: ED-26, N C. E. Pe Proc. IEE M. E. M Trans. UI No. 2, pp Pau-Ling	Dec. 1983. sylance, et al., "A Batch meter", <i>IEEE Trans. E</i> so. 12, pp. 1911-1917, Du tersen, "Silicon as a Mi E, vol. 70, No. 5, pp. 420 otamedi, "Acoustic Acc <i>trason. Ferroelec. Freq. Co.</i> . 237-242, Mar. 1987. Chem. et al., "Integrator	n-Fabricated Silicon lectron Devices, vol. sc. 1979. schanical Material", 0-457, May 1982. elerometers", <i>IEEE</i> ontr., vol. UFFC-34, 1 Silicon Microbeam





RIT'S FIRST MICRO MOTORS – SENIOR PROJECT



Matt Matessa, 1991, BSµE, Joined Cypress Semiconductor San Jose, CA





Rochester Institute of Technology Microelectronic Engineering

© November 28, 2011 Dr. Lynn Fuller

RIT'S FIRST PHOTONIC DEVICES – SENIOR PROJECT

Dave Borkholder, 1994, after graduation from RIT joined Ph.D. program in EE at Stanford University Palo Alto, CA



GaP wafers with n-type epilayer, add gold metal, dice and wire bond to RIT thick film ceramic package.

Rochester Institute of Technology Microelectronic Engineering

© November 28, 2011 Dr. Lynn Fuller

Page 9

HOT FILAMENT LIGHT SOURCES







CMOS OPERATIONAL AMPLIFIER – MASTERS THESIS



CMOS OPERATIONAL AMPLIFIER – MASTERS THESIS



Ed Sayer, MSEE 1991, joined Digital Equipment Corp., Hudson, MA

Rochester Institute of Technology

Microelectronic Engineering

© November 28, 2011 Dr. Lynn Fuller

TOP SIDE BULK MICROMACHINED PRESSURE SENSORS – SENIOR PROJECT



300 µm

Jason Trost, 1995 BSµE, joined Harris Semiconductor Mountaintop, PA Pressure Sensor with Nitride Diaphragm and Poly Piezo Resistors over Bulk Etched Cavity





Rochester Institute of Technology Microelectronic Engineering

© Nov ember 28, 2011 Dr. Lynn Fuller







History of MEMS at RIT NIH FUNDED RESEARCH ON PRESSURE SENSORS Vgate 000332 Vsource 15 µm **Vdrain** ×488 75 µm 111172B Poly Diaphragm 5x Vgate $2 \mu m n + Poly$ Aluminum Plug Vdrain Vsource **Etch Holes** l µm space (vacuum **Contact Cut** Ът D to Poly Gate 1000 Å Oxide Rochester Institute of Technology n-type silicon Microelectronic Engineering © November 28, 2011 Dr. Lynn Fuller Page 18





INCUBATOR – INTEGRATED NANO-TECHNOLOGIES, LLC



INT Bio-Detect Card



Rochester Institute of Technology Microelectronic Engineering



Chafin and Dr.

Because the DNA is hybridized to a probe DNA with 15 matching base pairs, the probability that the attached DNA is the desired DNA is one billion to one or better. $(i.e. 4^{15})$



© November 28, 2011 Dr. Lynn Fuller

FIRST MEMS PROJECT BETWEEN COE AND COS

CHEMIRESISTOR

Simple inter-digitated electrodes coated with a chemically sensitive layer that changes the resistance in response to a few ppm of some (or many) chemicals

Copper-substituted Phthalcyanine conductive polymer is sensitive to CCl4, NH3 and N2O

or Carbon Nano-Tubes and various polymers

> Dr. Lynn Fuller Dr. KSV Santhanam Yatin Prayag 1999

Rochester Institute of Technology

Microelectronic Engineering



Resistor with 25µm gaps 25µm length 7250µm width

© November 28, 2011 Dr. Lynn Fuller





FIRST MECHANICAL ENGINEERING MEMS RESEARCH PROJECT

FLOW PLATES FOR FUEL INJECTION

Variety of different size and shape holes etched through 500 µm thick silicon wafer



Dr. Risa Robinson Delphi Products, Inc.

Rochester Institute of Technology Microelectronic Engineering



© November 28, 2011 Dr. Lynn Fuller





FINITE ELEMENT ANALYSIS OF THERMAL BENDING





SHORT COURSE JULY 2000 EXAMPLE

Cantilevers Springs Accelerometer Electrostatic Comb Drive Mirrors Optical Modulators Optical Arrays Tweezers Inductors Contactors

> Rochester Institute of Technology Microelectronic Engineering



APRIL 1999 CLASS PROJECT

Cantilevers Springs Accelerometer **Electrostatic Comb Drive** Mirrors **Optical Modulators Optical Arrays** Tweezers Inductors Contactors







SEM PICTURES



VERIFICATION OF RELEASE



© Nov ember 28, 2011 Dr. Lynn Fuller


ELECTROSTATIC ACTUATION OF CANTILEVER





SURFACE MICROMACHINED GAS FLOW SENSOR







© November 28, 2011 Dr. Lynn Fuller





















TESTING OF PACKAGED PRESSURE SENSORS



SURFACE MICROMACHINED GAS FLOW SENSOR



L of heater & resistor = 1mm		
W (heater)	= 50um	
W (resistors)	= 20um	
Gap	= 10um	
V applied = $27V$ to $30.5V$		
Temp ~600 °C at 26 volts		
Lifetime > 10 min at 27 volts (possibly longer, did not test)		

Vee (Chee	Hwang,	2004
-------	------	--------	------

Rochester Institute of Technology Microelectronic Engineering

© Nov ember 28, 2011 Dr. Lynn Fuller

BULK MICROMACHINED GAS FLOW SENSOR



© November 28, 2011 Dr. Lynn Fuller





THERMIONIC GAS DETECTOR





MODIFIED BULK PROCESS FOR MEMS CLASS 2004-06

Pressure Sensor, diffused resistors or poly resistors Microphone- more sensitive pressure sensor Speaker – diaphragm with coil on it, magnet below Accelerometer – diaphragm with mass in center from back etch donut Diaphragm Actuator with coil and resistors for sensing and feedback Optical pyrometer with thermocouples on diaphragm Heater on diaphragm either poly or diffused resistor heater Heater plus temperature sensor (diffused heater, poly resistor sensor) Heater plus interdigitated chemical sensor Cantilever accelerometer with piezoresistors either poly or diffusion, mass from back etch donut Cantilever accelerometer with magnetic coil for sensor, mass from back etch donut Gas flow sensor single resistor anemometer Gas flow sensor with heater and two resistors Torsional mirror with coil actuators Gyroscope with piezoresistor sensors or coil and magnet sensors, with mass from back etch donut for each 1/2 of torsion bar Transistors and logic, RF Inductors

Rochester Institute of Technology Microelectronic Engineering

© Nov ember 28, 2011 Dr. Lynn Fuller

MODIFIED BULK PROCESS FOR MEMS CLASS 2004-06





Torisonal Mirror



© November 28, 2011 Dr. Lynn Fuller





VISCOCITY SENSOR JOURNAL PUBLICATION AND PATENT

Journal of Microelectromechanical Systems

A Joint IEEE and ASME Publication on Microstructures, Microactuators, Microsensors, and Microsystems



© November 28, 2011 Dr. Lynn Fuller



(19) United States

(12) Patent Application Publication (10) Pub. No.: US 2010/0332155 A1 Dec. 30, 2010

Publication Classification

(1)	Int. CL	
	G01N 11/00	(2006.01)
	H01L 21/70	(2006.01)
(2)	U.S. Cl	702/50; 73/54.42; 438/51; 438/53;
		257/E21.532

A viscosity measurement device includes a flexible membrane, an actuation heating element, and a displacement sensor apparatus. The actuation heating element is on and spaced in from an outer periphery of the flexible membrane. The displacement sensor apparatus is coupled to the flexible membrane and measures and outputs a displacement signal representative of a viscosity of a fluid in contact with the

MODIFIED BULK PROCESS FOR MEMS CLASS 2004-06





History of MEMS at RIT **SECOND VERSION COMPLETED DEVICES** W3 **W1** L2 **W**2 $W1 = 300 \ \mu m$ W2 = 1100W3 = 450L1 = 1400Rochester Institute of Technology Microelectronic Engineering L2 = 1250

© November 28, 2011 Dr. Lynn Fuller

MICROSPEAKER – CHRIS NASSER



Audio

> http://video.google.com/videoplay?docid=4513627860990043960

© November 28, 2011 Dr. Lynn Fuller



History of MEMS at RIT OIL QUALITY MEMS MULTI-SENSOR Photo Diode al Diffused Heater Actuator 0 0 5mm Pressure Sensor • Water in Oil × 5mm EIS Diode Picture of MEMS Multisensor Temperature Sensor Zero-Span Compensated Pressure Sensorover Tempe rature 100 Nyquist itent 50.00 1.40E+9 **Diode Temperature Sensor** 45.00 000054 40.00 Voltage [n 1.20E+9 35.00 5,00000 30.00 1.00E+9-25.00 Con SMLD Output 20.00 Vet 6 8000 8.00E+8 15.00 10.00 6.00E+8 5.00 0.00 10 15 5 20 4.00E+8 0 0000-00 2008-00 ∕₣ Pressure [psi] VA 2.00E+8 ← T = 27 C — T = 57 C → T = 84 C Temp Sensor Test 0.00--5.0E+8 0.0 5.0E+8 1.0E+9 1.5E+9 2.0E+9 2.5E+9 3.0E+9 3.5E+9 Oil with 1% Soot Pressure Study © November 28, 2011 Dr. Lynn Fuller Page 69



MULTISENSOR MICROSYSTEM



History of MEMS at RIT **TEAM GALT SUPPORTS OTHER FACULTY PROJECTS** Dr. David Borkholder – PI Blast Dosimeter / DARPA Blast Indicator Lights Gauge Sensor Dome Impact-Micro-USB Resistant Port Casing Blast Gauge: The data-logging device measures pressure, resulting head acceleration, and time to help correlate Explosives Testing: Weighted crash test dummies are used to simulate a soldier in the field. blast events with injuries. The compact device weighs less than one ounce, A number of orientations are used to allow the team to characterize the space and inform the device algorithms. making it easy for soldiers to wear.

© November 28, 2011 Dr. Lynn Fuller
ENERGY HARVESTING

Indirect Conversion of Radiation for 20 Year-Life Batteries

Green Optimized Photocell





Gaseous Tritium Light Source (GTLS)

(GTLS) – Phosphor Coat Glass Vial with Tritium Inside Tritium: Radioactive Isotope of Hydrogen, ³H, 12year half life Emits Electrons Through Beta Decay Electrons Interact With Phosphor Material Green Light is Emitted (Radio luminescence) Photo Detector Captures Light and Converts to Energy Energy Management Electronics Stores Energy in a Super Capacitor

© November 28, 2011 Dr. Lynn Fuller

Page 73

History of MEMS at RIT **VIBRATION ENERGY HARVESTER** Tektronix TDS 340 TMO CHANNEL ME OSCILLOSCOPE 1.750D 500 S/s : 40ms Ch1 Freq 30.3 Hz 30 Sep 201 Dr. Denis Cormier 3-D Printer Brinkman Lab at RIT Rochester Institute of Technology Microelectronic Engineering © Nov ember 28, 2011 Dr. Lynn Fuller Page 74



ACKNOWLEDGEMENTS

Dr. Richard Lane Dr. Risa Robinson Dr. Robert Pearson Dr. KSV Santhanam Dr. Sergey Lyshevski Dr. David Borkholder Dr. Karl Hirschman Matt Matessa Jon Stephan Ed Sayer Jason Trost

Kerstin Babbitt Stephanie Bennett Sheila Kawati An Pham Andrew Randles Kevin Munger Rob Manley Vee Chee Hwang Ivan Puchades Team Galt

Rochester Institute of Technology Microelectronic Engineering

© Nov ember 28, 2011 Dr. Lynn Fuller

Page 76

TEAM GALT



Tal, Lynn, Ellen Sedlack, Christian, Artur, Ivan, Renat



B.S., M.S., Ph.D., students from EE, ME, MicroE, CE, Materials Science



Heidi, Murat

© Nov ember 28, 2011 Dr. Lynn Fuller

Page 77

DR. FULLER'S STUDENTS IN EMCR 890 MEMS CLASS 2002



CONFERENCE PUBLICATIONS

1. "Nanocomposite Material for Sensing of Halogenated Methanes: A Model Based on Charge Transfer Interaction for Selectivity," R.Sangoi, L.Fuller, K.S.V. Santhanam, MRS Meeting, Boston, Massachusetts, October, 2003.

2. "Design and Analysis of a Shear Stress Sensor for Microcirculation Investigation," ASME Fluid Engineering Division July 6-10, 2003, Honolulu, Hawaii, L.F.Fuller, Risa Robinson, et.el.

3. "Bulk Micromachined Pressure Sensor," L.F.Fuller, Steve Sudirgo, Proceedings of the IEEE UGIM Conference, June 2003, Boise State University.

4. "An Inter-digitated Electrode Detector for the Identification of a Single Specific DNA Molecule Fragment," L.F.Fuller, Renaldo Vega, Robert Manley, Vee Chee Hwang, Dan Jansen, An Pham, Nate Wescott, Mike Connolly, Proceedings of the IEEE UGIM Conference, June 2003, Boise State University.

5. 'Fabrication of Polysilicon Surface Micromachined MEMs Structures', Kevin Munger and Lynn F. Fuller, Microelectronic Engineering, Rochester Institute of Technology, Proceedings of the IEEE UGIM Conference, June 2001, Virginia Commonwealth University.

6. "MEMS Activity at Rochester Institute of Technology," L.F.Fuller, A.Pham, P. Merwah, Proceedings of the IEEE UGIM Conference, June 20-23, 1999, Minneapolis, MN

7. "A Surface Micromachined Capacitive Pressure Sensor for Biomedical Applications," K.E.Babbitt, L.F.Fuller, B.Keller, Proceedings of the IEEE UGIM Conference, July 20-23, 1997, Rochester, NY

8. "A Multi-project MEMs Leture and Laboratory Course," L.F.Fuller, Proceedings of the IEEE UGIM Conference, July 20-23, 1997, Rochester, NY

9. "Microelectronic Engineering at RIT - The First 10 Years", L.F.Fuller, R.E.Pearson, S.K.Kurinec, I.R.Turkman, M.A.Jackson, B.W.Smith, R.L.Lane, Proceedings of the 10th Biennial University Industry Government Microelectronics Symposium, May 1993, Durham NC.

